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Docket No.: 4590-337

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of :
Emmanuel DE CHAMBOST *et al.* : Confirmation No. 8085
U.S. Patent Application No. 10/508,834 : Allowed: December 1, 2005
Filed: September 23, 2004 : Group Art Unit: 2881
Examiner: Jack I. Berman

For: DEVICE FOR MEASURING THE EMISSION OF X RAYS PRODUCED BY AN
OBJECT EXPOSED TO AN ELECTRON BEAM

REQUEST FOR ACKNOWLEDGEMENT AND ACCEPTANCE OF DRAWINGS

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

We are in receipt of the Notice of Allowance and Allowability of the above-identified application mailed December 1, 2005. In the current Notice of Allowability, the Examiner does not indicate if the drawings submitted to the U.S. Patent Office on September 23, 2004 are acceptable.

Applicants hereby request that the previously filed drawings be immediately acknowledged and a Notice confirming that the drawings are acceptable be furnished to the undersigned.

Respectfully submitted,

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